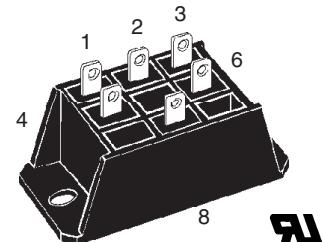
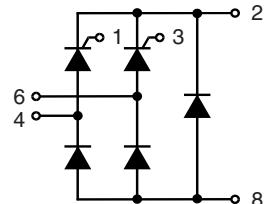


# Half Controlled Single Phase Rectifier Bridge with Freewheeling Diode

$I_{dAVM} = 40 \text{ A}$   
 $V_{RRM} = 1400 \text{ V}$

| $V_{RSM}$ | $V_{RRM}$ | Type         |
|-----------|-----------|--------------|
| $V_{DSM}$ | $V_{DRM}$ |              |
| V         | V         |              |
| 1500      | 1400      | VHF 36-14io5 |



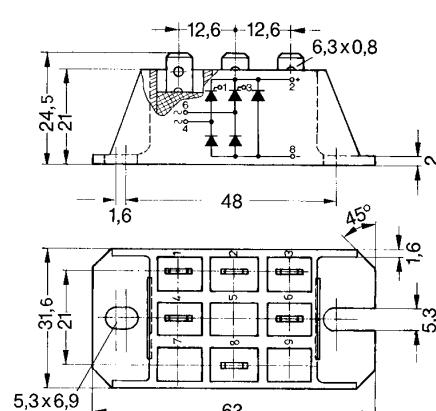
| Symbol               | Test Conditions  | Maximum Ratings   |  | Features                              |
|----------------------|--|---|--|---------------------------------------|
| $I_{dAV}$            | $T_K = 85^\circ\text{C}$ , module  | 36  | A  | • Package with DCB ceramic base plate |
| $I_{dAVM}$ ①         | module   | 40  | A  | • Isolation voltage 3600 V~           |
| $I_{FRMS}, I_{TRMS}$ | per leg  | 28  | A  | • Planar passivated chips             |
| $I_{FSM}, I_{TSM}$   | $T_{VJ} = 45^\circ\text{C}$ ;<br>$V_R = 0 \text{ V}$   | 320   | A  | • 1/4" fast-on terminals              |
|                      | $t = 10 \text{ ms}$ (50 Hz), sine<br>$t = 8.3 \text{ ms}$ (60 Hz), sine  | 350   | A  | • UL registered E 72873               |
|                      | $T_{VJ} = T_{VJM}$<br>$V_R = 0 \text{ V}$  | 280   | A  |                                       |
|                      | $t = 10 \text{ ms}$ (50 Hz), sine<br>$t = 8.3 \text{ ms}$ (60 Hz), sine  | 310   | A  |                                       |
| $I^2t$               | $T_{VJ} = 45^\circ\text{C}$<br>$V_R = 0 \text{ V}$   | 500   | $\text{A}^2\text{s}$                     |                                       |
|                      | $T_{VJ} = T_{VJM}$<br>$V_R = 0 \text{ V}$  | 320   | $\text{A}^2\text{s}$                     |                                       |
|                      | $t = 10 \text{ ms}$ (50 Hz), sine<br>$t = 8.3 \text{ ms}$ (60 Hz), sine  | 390   | $\text{A}^2\text{s}$                     |                                       |
|                      |  | 400   | $\text{A}^2\text{s}$                     |                                       |
| $(di/dt)_{cr}$       | $T_{VJ} = 125^\circ\text{C}$<br>$f = 50 \text{ Hz}$ , $t_p = 200 \mu\text{s}$<br>$V_D = 2/3 V_{DRM}$<br>$I_G = 0.3 \text{ A}$ ,<br>$di_G/dt = 0.3 \text{ A}/\mu\text{s}$ | repetitive, $I_T = 50 \text{ A}$<br><br>non repetitive, $I_T = 1/2 \cdot I_{dAV}$ | 150                                      | $\text{A}/\mu\text{s}$                |
| $(dv/dt)_{cr}$       | $T_{VJ} = T_{VJM}$ ; $V_{DR} = 2/3 V_{DRM}$<br>$R_{GK} = \infty$ ; method 1 (linear voltage rise)  |   | 1000                                     | $\text{V}/\mu\text{s}$                |
| $V_{RGM}$            |  |   | 10                                       | V                                     |
| $P_{GM}$             | $T_{VJ} = T_{VJM}$<br>$I_T = I_{TAVM}$   | $t_p = 30 \mu\text{s}$<br>$t_p = 500 \mu\text{s}$<br>$t_p = 10 \text{ ms}$        | $\leq 10$<br>$\leq 5$<br>$\leq 1$<br>0.5 | W                                     |
| $P_{GAVM}$           |  |   |  | W                                     |
| $T_{VJ}$             |  |   | -40...+125                               | $^\circ\text{C}$                      |
| $T_{VJM}$            |  |   | 125                                      | $^\circ\text{C}$                      |
| $T_{stg}$            |  |   | -40...+125                               | $^\circ\text{C}$                      |
| $V_{ISOL}$           | 50/60 Hz, RMS<br>$I_{ISOL} < 1 \text{ mA}$   | $t = 1 \text{ min}$<br>$t = 1 \text{ s}$  | 3000<br>3600                             | $\text{V}_\sim$                       |
| $M_d$                | Mounting torque  | (M5)<br>(10-32 UNF)   | 2-2.5<br>18-22                           | Nm<br>lb.in.                          |
| <b>Weight</b>        |  |   | 50                                       | g                                     |

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.  
① for resistive load.

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Dimensions in mm (1 mm = 0.0394")



| Symbol               | Test Conditions   | Characteristic Values                      |                    |    |
|----------------------|---|--|--------------------|----|
| $I_R, I_D$           | $V_R = V_{RRM}; V_D = V_{DRM}$<br>$T_{VJ} = T_{VJM}$<br>$T_{VJ} = 25^\circ C$   | $\leq 5$                                   | mA                 |    |
|                      |   | $\leq 0.3$                                 | mA                 |    |
| $V_T, V_F$           | $I_T, I_F = 45 A; T_{VJ} = 25^\circ C$  | $\leq 1.45$                                | V                  |    |
| $V_{T0}$<br>$r_T$    | For power-loss calculations only ( $T_{VJ} = 125^\circ C$ )   | 0.85                                       | V                  |    |
|                      |   | 13   | $m\Omega$          |    |
| $V_{GT}$             | $V_D = 6 V;$<br>$T_{VJ} = 25^\circ C$<br>$T_{VJ} = -40^\circ C$   | $\leq 1.0$                                 | V                  |    |
|                      | $T_{VJ} = 25^\circ C$<br>$T_{VJ} = -40^\circ C$<br>$T_{VJ} = 125^\circ C$   | $\leq 1.2$                                 | V                  |    |
| $I_{GT}$             | $V_D = 6 V;$<br>$T_{VJ} = 25^\circ C$<br>$T_{VJ} = -40^\circ C$<br>$T_{VJ} = 125^\circ C$   | $\leq 65$                                  | mA                 |    |
|                      |   | $\leq 80$                                  | mA                 |    |
|                      |   | $\leq 50$                                  | mA                 |    |
| $V_{GD}$<br>$I_{GD}$ | $T_{VJ} = T_{VJM};$<br>$T_{VJ} = T_{VJM};$  | $V_D = 2/3 V_{DRM}$<br>$V_D = 2/3 V_{DRM}$ | $\leq 0.2$         | V  |
|                      |   |  | $\leq 5$           | mA |
| $I_L$                | $I_G = 0.3 A; t_G = 30 \mu s;$<br>$di_G/dt = 0.3 A/\mu s;$<br>$T_{VJ} = 25^\circ C$<br>$T_{VJ} = -40^\circ C$<br>$T_{VJ} = 125^\circ C$ | $\leq 150$                                 | mA                 |    |
|                      |   | $\leq 200$                                 | mA                 |    |
|                      |   | $\leq 100$                                 | mA                 |    |
| $I_H$                | $T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$   | $\leq 100$                                 | mA                 |    |
| $t_{gd}$             | $T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$<br>$I_G = 0.3 A; di_G/dt = 0.3 A/\mu s$  | $\leq 2$                                   | $\mu s$            |    |
| $t_q$<br>$Q_r$       | $T_{VJ} = 125^\circ C, I_T = 15 A, t_p = 300 \mu s, V_R = 100 V$<br>$di/dt = -10 A/\mu s, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$        | typ.<br>150<br>75                          | $\mu s$<br>$\mu C$ |    |
| $R_{thJC}$           | per thyristor (diode); DC current   | 1.15                                       | K/W                |    |
|                      | per module  | 0.29                                       | K/W                |    |
| $R_{thJK}$           | per thyristor (diode); DC current   | 1.55                                       | K/W                |    |
|                      | per module  | 0.39                                       | K/W                |    |
| $d_s$                | Creeping distance on surface  | 12.6                                       | mm                 |    |
| $d_A$                | Creepage distance in air  | 6.3  | mm                 |    |
| $a$                  | Max. allowable acceleration   | 50   | $m/s^2$            | 10 |

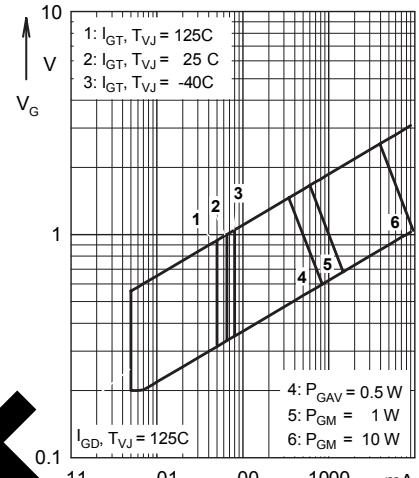
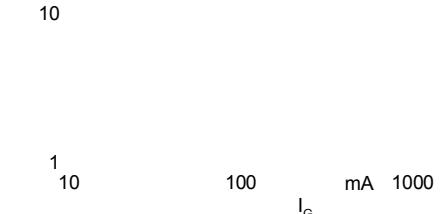
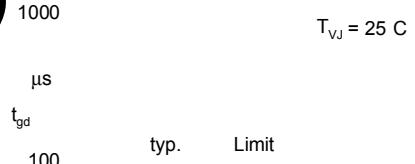


Fig. 1 Gate trigger range

Fig. 2 Gate controlled delay time  $t_{gd}$

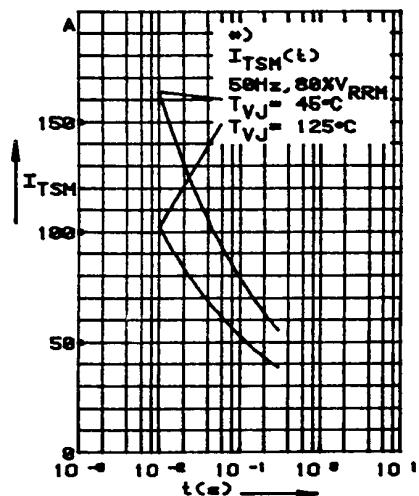


Fig. 3 Surge overload current per chip  
 $I_{TSM}$ : Crest value, t: duration

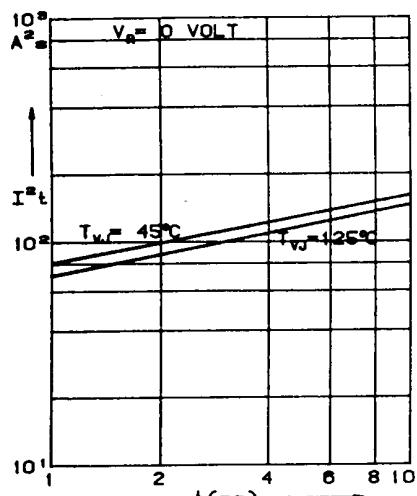


Fig. 4  $I^2t$  versus time (1-10 ms)  
per chip

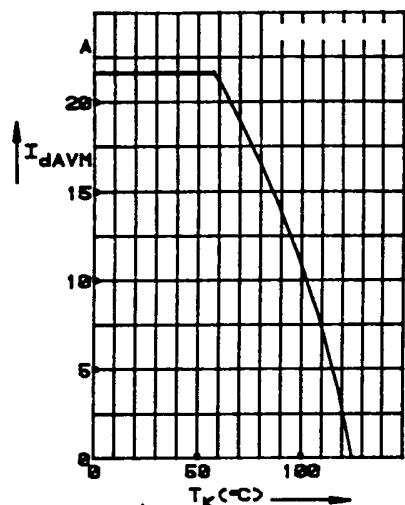


Fig. 5 Max. forward current at  
heatsink temperature

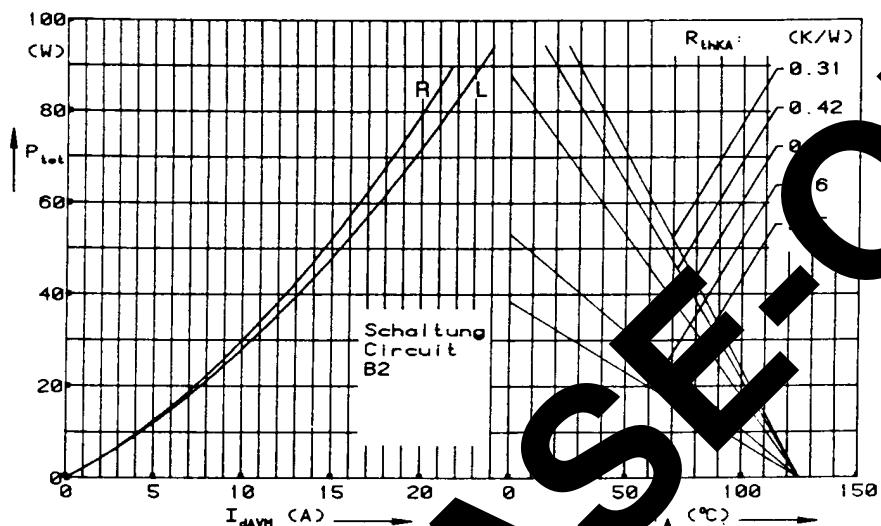


Fig. 6 Power dissipation versus direct output current and ambient temperature

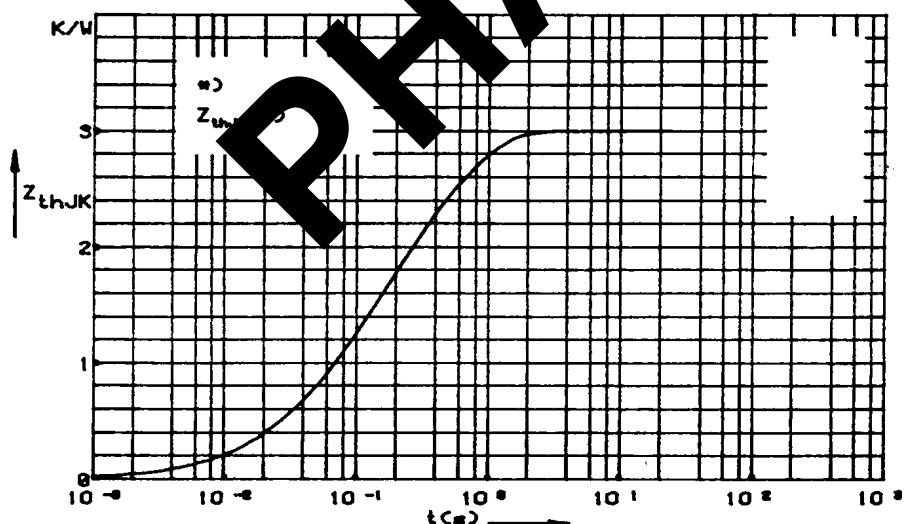


Fig. 7 Transient thermal impedance junction to heatsink per chip  
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Constants for  $Z_{thJK}$  calculation:

| i | $R_{thi}$ (K/W) | $t_i$ (s) |
|---|-----------------|-----------|
| 1 | 0.34            | 0.0344    |
| 2 | 1.16            | 0.12      |
| 3 | 1.5             | 0.5       |